TEST LOG



Article number:	A153460WS003	Sprache Language ODE OEN OFR ONL OES	OPI
		Date: 18.10.202	1
Device status:		Bemerkungen / Remarks:	
■ As good as new unused		OVP beschädigt	
Damaged (light) technically inspected			
Damaged (dents/scratches) technically checked			
Signs of wear (lig	ght) technically checked		
Traces of use te	chnically checked		

Trade fair / customer return, technically checked and fully functional.

Unit may show slight signs of use and/or slight packaging damage.